



SCOPE OF ACCREDITATION TO ISO/IEC 17025:2005  
& ANSI/NCSL Z540-1-1994

GRAND RAPIDS METROLOGY  
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CALIBRATION

Valid To: January 31, 2018

Certificate Number: 1489.01

In recognition of the successful completion of the A2LA evaluation process, accreditation is granted to this laboratory to perform the following calibrations<sup>1</sup>:

I. Dimensional

Parameter/Equipment	Range	CMC <sup>2,4</sup> (±)	Comments <sup>5</sup>
Angle Blocks	Up to 90°	0.02°	Optical Comparator, angle blocks
Calipers <sup>3</sup>	Up to 24 in (< 24 to 60) in	(300 + 10L) μin (1400 + 1.2L) μin	Gage blocks
Cylindrical Pins	Up to 1 in	(13 + 8D) μin	P&W Labmaster™, gage block masters
	Up to 1 in	46 μin	Mitutoyo laser micrometer, gage block masters
Cylindrical Ring Gages	(0.25 to 12) in	(18 + 7D) μin	P&W Labmaster™, master rings
Dial Indicators <sup>3</sup>	Up to 4 in	(76 + 91L) μin	Gage blocks
Feeler Gages	Up to 0.05 in	(18 + 7L) μin	P&W Labmaster™ <sub>r</sub> , gage block masters

Parameter/Equipment	Range	CMC <sup>2,4</sup> ( $\pm$ )	Comments <sup>5</sup>	
Gage Balls	(0.125 to 1) in	$(20 + 7D) \mu\text{in}$	P&W Labmaster <sup>TM</sup> , gage block masters	
Gage Blocks	(0.005 to 12) in	$(12 + 8L) \mu\text{in}$	P&W Labmaster <sup>TM</sup> , gage block masters	
Height Gages <sup>3</sup>	Up to 40 in	$(600 + 41L) \mu\text{in}$	Gage blocks	
Snap Gages	(0.25 to 14) in	$(18 + 7L) \mu\text{in}$	P&W Labmaster <sup>TM</sup> , master rings	
	(14 to 24) in	$(55 + 8L) \mu\text{in}$	Gage blocks	
Bore Gage	Up to 2 in	58 $\mu\text{in}$	Master rings	
Micrometers <sup>3</sup> – Outside	Up to 6 in ( $< 6$ to 60) in	$(55 + 8L) \mu\text{in}$ $(530 + 5L) \mu\text{in}$	Gage blocks	
Optical Comparator <sup>3</sup> –				
	Axis Linearity	12 in	$(260 + 0.5L) \mu\text{in}$	Glass master scales, angle blocks
	Magnification	(10, 20, 50, 100, 125, 250) x	$(620 + 0.5L) \mu\text{in}$	
Angle	Up to 360°	0.3°		
Rules	Up to 72 in	0.6R	Gage blocks	
Thread Plugs –			P&W Labmaster <sup>TM</sup> , gage block masters, thread wire masters	
	Pitch Diameter	Up to 4 in		$(88 + 6D) \mu\text{in}$
Major Diameter	Up to 4 in	$(13 + 8D) \mu\text{in}$		
Thread Wires	Up to 0.500 in diameter	$(31 + 6D) \mu\text{in}$	P&W Labmaster <sup>TM</sup> , gage block masters, thread wire masters	
Protractors	Up to 360°	0.08°	Sine plate and gage blocks	

Parameter/Equipment	Range	CMC <sup>2,4</sup> (±)	Comments
Surface Plates <sup>3</sup> –			
Flatness	Up to 144 in	(72 + 0.3L) μin	Planekator
Repeatability	Up to 144 in	49 μin	Repeat-O-Meter

## II. Electrical – DC/Low Frequency

Parameter/Equipment	Range	CMC <sup>2,4,6</sup> (±)	Comments
DC Voltage – Generate	(0 to 330) mV 330mV to 3.3 V (3.3 to 33) V (33 to 330) V (100 to 1000) V	20 μV/V + 1 μV 11 μV/V + 2 μV 12 μV/V + 20 μV 18 μV/V + 150 μV 18 μV/V + 1.5 mV	Fluke 5522A
DC Voltage – Measure	(0 to 100) mV 100 mV to 1 V (1 to 10) V (10 to 100) V (100 to 1000) V	14 μV/V + 3 μV 7 μV/V + 0.3 μV 6 μV/V + 0.05 μV 10 μV/V + 0.3 μV 9 μV/V + 0.1 μV	Hewlett Packard 3458A opt 002
DC Current – Measure	(0 to 100) nA 100 nA to 1μA (1 to 10) μA (10 to 100) μA 100 μA to 1 mA (1 to 10) mA (10 to 100) mA 100 mA to 1 A  (1 to 100) A (100 to 500) A (500 to 1000) A (1000 to 1500) A	58 μA/A + 400 μA 89 μA/A + 40 μA 66 μA/A + 10 μA 29 μA/A + 8 μA 25 μA/A + 5 μA 25 μA/A + 5 μA 40 μA/A + 5 μA 120 μA/A + 10 μA  0.29 % 1.4 % 2.9 % 4.3 %	Hewlett Packard 3458A opt 002  Empro Shunt w/ Agilent 3458A

Parameter/Equipment	Range	CMC <sup>2, 4, 6</sup> (±)	Comments
DC Current – Generate	(0 to 330) $\mu$ A (0 to 3.3) mA (0 to 33) mA (0 to 330) mA (0 to 1.1) A (1.1 to 3) A (0 to 11) A (11 to 20.5) A	0.26 % + 0.02 $\mu$ A 0.029 % + 0.05 $\mu$ A 0.011 % + 0.25 $\mu$ A 0.024 % + 2.5 $\mu$ A 0.024 % + 40 $\mu$ A 0.039 % + 40 $\mu$ A 0.055 % + 500 $\mu$ A 0.10 % + 750 $\mu$ A	Fluke 5522A
Resistance – Generate	(0 to 11) $\Omega$ (11 to 33) $\Omega$ (33 to 110) $\Omega$ (110 to 330) $\Omega$ (0.33 to 1.1) k $\Omega$ (1.1 to 3.3) k $\Omega$ (3.3 to 11) k $\Omega$ (11 to 33) k $\Omega$ (33 to 110) k $\Omega$ (110 to 330) k $\Omega$ (0.33 to 1.1) M $\Omega$ (1.1 to 3.3) M $\Omega$ (3.3 to 11) M $\Omega$ (11 to 33) M $\Omega$ (33 to 110) M $\Omega$ (110 to 330) M $\Omega$ (0.33 to 1.1) G $\Omega$	41 $\mu\Omega/\Omega$ + 0.001 $\Omega$ 30 $\mu\Omega/\Omega$ + 0.0015 $\Omega$ 29 $\mu\Omega/\Omega$ + 0.0014 $\Omega$ 28 $\mu\Omega/\Omega$ + 0.002 $\Omega$ 28 $\mu\Omega/\Omega$ + 0.002 $\Omega$ 28 $\mu\Omega/\Omega$ + 0.02 $\Omega$ 28 $\mu\Omega/\Omega$ + 0.02 $\Omega$ 28 $\mu\Omega/\Omega$ + 0.2 $\Omega$ 28 $\mu\Omega/\Omega$ + 0.2 $\Omega$ 32 $\mu\Omega/\Omega$ + 2 $\Omega$ 33 $\mu\Omega/\Omega$ + 2 $\Omega$ 60 $\mu\Omega/\Omega$ + 30 $\Omega$ 0.013 % + 50 $\Omega$ 0.025 % + 2.5 k $\Omega$ 0.051 % + 3 k $\Omega$ 0.30 % + 100 k $\Omega$ 1.5 % + 500 k $\Omega$	Fluke 5522A
Resistance – Measure	(0 to 10) $\Omega$ (10 to 100) $\Omega$ 100 $\Omega$ to 1 k $\Omega$ (1 to 10) k $\Omega$ (10 to 100) k $\Omega$ 100 k $\Omega$ to 1 M $\Omega$ (1 to 10) M $\Omega$ (10 to 100) M $\Omega$ 100 M $\Omega$ to 1 G $\Omega$	22 $\mu\Omega/\Omega$ + 50 $\mu\Omega$ 18 $\mu\Omega/\Omega$ + 0.5 $\mu\Omega$ 11 $\mu\Omega/\Omega$ + 0.5 m $\Omega$ 11 $\mu\Omega/\Omega$ + 5 m $\Omega$ 11 $\mu\Omega/\Omega$ + 50 m $\Omega$ 19 $\mu\Omega/\Omega$ + 2 $\Omega$ 61 $\mu\Omega/\Omega$ + 100 $\Omega$ 0.052 % + 1 k $\Omega$ 0.52 % + 10 k $\Omega$	Hewlett Packard 3458A opt 002

Parameter/Range	Frequency	CMC <sup>2,6</sup> (±)	Comments
Capacitance – Generate			
(220 to 399.9) pF	(10 to 10 000) Hz	0.41 % + 10 pF	Fluke 5522A
(0.4 to 1.0999) nF	(10 to 10 000) Hz	0.39 % + 0.01 nF	
(1.1 to 3.2999) nF	(10 to 3000) Hz	0.39 % + 0.01 nF	
(3.3 to 10.9999) nF	(10 to 1000) Hz	0.20 % + 0.01 nF	
(11 to 32.9999) nF	(10 to 1000) Hz	0.19 % + 0.01 nF	
(33 to 109.999) nF	(10 to 1000) Hz	0.19 % + 0.01 nF	
(110 to 329.999) nF	(10 to 1000) Hz	0.19 % + 0.03 nF	
(0.33 to 1.09999) μF	(10 to 600) Hz	0.56 % + 1 nF	
(1.1 to 3.29999) μF	(10 to 300) Hz	0.26 % + 3 nF	
(3.3 to 10.9999) μF	(10 to 150) Hz	0.20 % + 10 nF	
(11 to 32.9999) μF	(10 to 120) Hz	0.31 % + 30 nF	
(33 to 109.999) μF	(10 to 80) Hz	0.35 % + 100 nF	
(110 to 329.999) μF	(0 to 50) Hz	0.35 % + 300 nF	
(0.33 to 1.09999) mF	(0 to 20) Hz	0.35 % + 1 μF	
(1.1 to 3.29999) mF	(0 to 6) Hz	0.35 % + 3 μF	
(3.3 to 10.9999) mF	(0 to 2) Hz	0.35 % + 10 μF	
(11 to 32.9999) mF	(0 to 0.6) Hz	0.60 % + 30 μF	
(33 to 110) mF	(0 to 0.2) Hz	0.43 % + 100 μF	

Parameter/Range	Frequency	CMC <sup>2,6</sup> (±)	Comments
AC Voltage – Generate			
(1 to 33) mV	(10 to 45) Hz 45 Hz to 10 kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 500) kHz	0.10 % + 6 μV 0.042 % + 6 μV 0.046 % + 6 μV 0.12 % + 6 μV 0.39 % + 12 μV 0.95 % + 50 μV	Fluke 5522A
(33 to 330) mV	(10 to 45) Hz (45 Hz to 10 kHz) (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 500) kHz	0.042 % + 8 μV 0.032 % + 8 μV 0.033 % + 8 μV 0.046 % + 8 μV 0.094 % + 32 μV 0.22 % + 70 μV	
(0.33 to 3.3) V	(10 to 45) Hz 45 Hz to 10 kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 500) kHz	0.041 % + 50 μV 0.031 % + 60 μV 0.034 % + 60 μV 0.041 % + 50 μV 0.078 % + 130 μV 0.26 % + 600 μV	
(3.3 to 33) V	(10 to 45) Hz (45 Hz to 10 kHz) (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz	0.24 % + 650 μV 0.031 % + 600 μV 0.037 % + 600 μV 0.045 % + 600 μV 0.098 % + 1.6 mV	
(33 to 330) V	(45 Hz to 1 kHz) (1 to 10) kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz	0.020 % + 2 mV 0.022 % + 6 mV 0.027 % + 6 mV 0.032 % + 6 mV 0.22 % + 50 mV	
(330 to 1020) V	45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz	0.031 % + 10 mV 0.026 % + 10 mV 0.031 % + 10 mV	
AC Voltage – Measure			
Up to 10 mV	(1 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz	0.030 % + 0.03 % 0.020 % + 0.011 % 0.030 % + 0.011 % 0.10 % + 0.011 % 0.50 % + 0.011 % 4.0 % + 0.02 %	Hewlett Packard 3458A opt 002

Parameter/Range	Frequency	CMC <sup>2,6</sup> (±)	Comments
AC Voltage – Measure (cont)			
10 mV to 10 V	(1 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz 300 kHz to 1 MHz (1 to 2) MHz	0.007 % + 0.004 % 0.007 % + 0.002 % 0.014 % + 0.002 % 0.030 % + 0.002 % 0.080 % + 0.002 % 0.30 % + 0.03 % 1.0 % + 0.01 % 1.5 % + 0.01 %	Hewlett Packard 3458A opt 002
(10 to 100) V	(1 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz 300 kHz to 1 MHz	0.020 % + 0.004 % 0.020 % + 0.002 % 0.020 % + 0.002 % 0.035 % + 0.002 % 0.12 % + 0.002 % 0.40 % + 0.01 % 1.5 % + 0.01 %	
(100 to 1000) V	(1 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz	0.040 % + 0.004 % 0.040 % + 0.002 % 0.060 % + 0.002 % 0.12 % + 0.002 % 0.30 % + 0.002 %	
AC Current – Generate			
(29 to 330) μA	(10 to 20) Hz (20 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz (10 to 30) kHz	0.23 % + 0.1 μA 0.32 % + 0.1 μA 0.16 % + 0.1 μA 0.35 % + 0.15 μA 0.86 % + 0.2 μA 1.7 % + 50 μA	Fluke 5522A

Parameter/Range	Frequency	CMC <sup>2,6</sup> (±)	Comments
AC Current – Generate (cont)			
(0.33 to 3.3) mA	(10 to 20) Hz (20 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz (10 to 30) kHz	0.21 % + 0.15 μA 0.13 % + 0.15 μA 0.11 % + 0.1 μA 0.21 % + 0.2 μA 0.51 % + 0.3 μA 1.0 % + 0.6 μA	Fluke 5522A
(3.3 to 33) mA	(10 to 20) Hz (20 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz (10 to 30) kHz	0.19 % + 2 μA 0.10 % + 2 μA 0.053 % + 2 μA 0.090 % + 2 μA 0.21 % + 3 μA 0.41 % + 4 μA	
(33 to 330) mA	(10 to 20) Hz (20 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz (10 to 30) kHz	0.19 % + 20 μA 0.10 % + 20 μA 0.053 % + 20 μA 0.12 % + 50 μA 0.23 % + 100 μA 0.46 % + 200 μA	
(0.33 to 1.1) A	(10 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz	0.21 % + 100 μA 0.098 % + 100 μA 0.70 % + 1 mA 3.0 % + 5 mA	
(1.1 to 3) A	(10 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz	0.19 % + 100 μA 0.070 % + 100 μA 0.63 % + 1 mA 2.7 % + 5 mA	
(3 to 11) A	(45 to 100) Hz 100 Hz to 1 kHz (1 to 5) kHz	0.080 % + 2 mA 0.12 % + 2 mA 3.0 % + 2 mA	
(11 to 20.5) A	(45 to 100) Hz 100 Hz to 1 kHz (1 to 5) kHz	0.15 % + 5 mA 0.18 % + 5 mA 3.0 % + 5 mA	



Parameter/Range	Frequency	CMC <sup>2,6</sup> (±)	Comments
AC Current – Measure			
(0 to 100) μA	(10 to 20) Hz (20 to 45) Hz 45 Hz to 100 Hz 100 Hz to 5 kHz	0.40 % + 0.03 % 0.15 % + 0.03 % 0.060 % + 0.03 % 0.060 % + 0.03 %	Hewlett Packard 3458A opt 002
(1 to 100) mA	(10 to 20) Hz (20 to 45) Hz (45 to 100) Hz 100 Hz to 5 kHz (5 to 20) kHz (20 to 50) kHz (50 to 100) kHz	0.40 % + 0.02 % 0.15 % + 0.03 % 0.060 % + 0.02 % 0.030 % + 0.02 % 0.060 % + 0.02 % 0.40 % + 0.04 % 0.55 % + 0.15%	
(0.1 to 1) A	(10 to 20) Hz (20 to 45) Hz (45 to 100) Hz 100 Hz to 5 kHz (5 to 20) kHz (20 to 50) kHz	0.40 % + 0.02 % 0.16 % + 0.02 % 0.080 % + 0.02 % 0.10 % + 0.02 % 0.30 % + 0.02 % 1.0 % + 0.04 %	
Oscilloscopes –			
Square Wave Signal: (1 kHz Input) 50 Ω Load @ 1 kHz 1 MΩ Load @ 1 kHz	1 mV to 6.6 V <sub>pk-pk</sub> 1 mV to 130 V <sub>pk-pk</sub>	0.19 % + 40 μV 0.08 % + 40 μV	Fluke 5522A SC1100
DC Volt Amplitude:			
50 Ω Load 1 MΩ Load	(0 to 6.6) V (0 to 130) V	0.19 % + 40 μV 0.04 % + 40 μV	
Leveled Sine Wave: Frequency	(0 to 1100) MHz	2.3 μHz/Hz	
Leveled Sine Wave Amplitude	50 kHz (Reference) 50 kHz to 100 MHz (100 to 300) MHz (300 to 600) MHz (600 to 1100) MHz	1.6 % + 300 μV 2.7 % + 300 μV 3.1 % + 300 μV 4.7 % + 300 μV 5.4 % + 300 μV	
Flatness (Bandwidth)	50 kHz to 100 MHz (100 to 300) MHz (300 to 600) MHz (600 to 1100) MHz	1.2 % + 100 μV 1.6 % + 100 μV 3.1 % + 100 μV 3.9 % + 100 μV	
Time Marker	5 s to 50 ms 20 ms to 1 ns	(19 + 1000 <i>t</i> ) μs/s 1.4 μs/s	
Rise Time	≥ 300 ps	79 ps	<i>t</i> = time in seconds

Parameter/Equipment	Range	CMC <sup>2</sup> (±)	Comments
Electrical Calibration of RTD Indicators –			
Pt 385, 100 Ω	(-200 to -80) °C (-80 to 0) °C (0 to 100) °C (100 to 300) °C (300 to 400) °C (400 to 630) °C (630 to 800) °C	0.06 °C 0.06 °C 0.09 °C 0.1 °C 0.1 °C 0.2 °C 0.3 °C	Fluke 5522A
Pt 385, 200 Ω	(-200 to -80) °C (-80 to 0) °C (0 to 100) °C (100 to 260) °C (260 to 300) °C (300 to 400) °C (400 to 600) °C (600 to 630) °C	0.05 °C 0.05 °C 0.05 °C 0.07 °C 0.2 °C 0.2 °C 0.2 °C 0.2 °C	
Pt 385, 500 Ω	(-200 to -80) °C (-80 to 0) °C (0 to 100) °C (100 to 260) °C (260 to 300) °C (300 to 400) °C (400 to 600) °C (600 to 630) °C	0.05 °C 0.06 °C 0.06 °C 0.07 °C 0.1 °C 0.1 °C 0.1 °C 0.2 °C	

Parameter/Equipment	Range	CMC <sup>2</sup> (±)	Comments
Electrical Calibration of RTD Indicators – (cont)			
Pt 385, 1000 Ω	(-200 to -80) °C (-80 to 0) °C (0 to 100) °C (100 to 260) °C (260 to 300) °C (300 to 400) °C (400 to 600) °C (600 to 630) °C	0.04 °C 0.04 °C 0.05 °C 0.06 °C 0.08 °C 0.08 °C 0.09 °C 0.3 °C	Fluke 5522A
Pt 3916, 100 Ω	(-200 to -190) °C (-190 to -80) °C (-80 to 0) °C (0 to 100) °C (100 to 260) °C (260 to 300) °C (300 to 400) °C (400 to 600) °C (600 to 630) °C	0.3 °C 0.06 °C 0.06 °C 0.08 °C 0.09 °C 0.1 °C 0.2 °C 0.2 °C 0.2 °C	
Pt 3926, 100 Ω	(-200 to -80) °C (-80 to 0) °C (0 to 100) °C (100 to 300) °C (300 to 400) °C (400 to 630) °C	0.06 °C 0.06 °C 0.09 °C 0.2 °C 0.2 °C 0.2 °C	
PtNi 385, 100 Ω	(-80 to 0) °C (0 to 100) °C (100 to 260) °C	0.1 °C 0.1 °C 0.2 °C	
Cu 427, 10 Ω	(-100 to 260) °C	0.4 °C	

Parameter/Equipment	Range	CMC <sup>2</sup> (±)	Comments
Thermocouple Simulation –			
Type E	(-200 to -100) °C (-100 to 600) °C (600 to 1000) °C	0.7 °C 0.7 °C 0.8 °C	Fluke 744
Type J	(-200 to -100) °C (-100 to 800) °C (800 to 1200) °C	0.7 °C 0.8 °C 0.8 °C	Fluke 744
Type K	(-200 to -100) °C (-100 to 400) °C (400 to 1200) °C (1200 to 1372) °C	0.8 °C 0.6 °C 0.9 °C 0.7 °C	Fluke 744
Type R	(0 to 100) °C (100 to 1767) °C	2 °C 2 °C	Fluke 744
Type S	(0 to 200) °C (200 to -1400) °C (1400 to 1767) °C	2 °C 2 °C 2 °C	Fluke 744
Type T	(-200 to 0) °C (0 to 400) °C	0.8 °C 0.6 °C	Fluke 744

### III. Mechanical

Parameter/Equipment	Range	CMC <sup>2,4</sup> (±)	Comments
Torque – Measuring Devices	Up to 250 ft·lbf	0.05 % of reading	Torque standards, load cells
Torque <sup>3</sup> – Wrenches	(5 to 50) ft·lbf (20 to 200) ft·lbf (50 to 500) ft·lbf (100 to 1000) ft·lbf	0.66 % full scale 0.66 % full scale 0.66 % full scale 0.66 % full scale	Torque transducers
Pressure – Hydraulic	(5 to 10 000) psi	0.6 % of reading	Ashcroft dead weight tester
Force <sup>3</sup> – Gages	Up to 1000 lbf	1.7R	Verification with ASTM class 6 weights
Transducers	Up to 1000 lbf (1000 to 50 000) lbf Up to 500 000 lbf (Compression)	0.06 % full scale 0.05 % full scale 0.09 % full scale	Load cell and meter
Analytical Balances <sup>3</sup>	(0 to 300) g	0.59 mg	Verification with Class 1 weights

Parameter/Equipment	Range	CMC <sup>2,4</sup> (±)	Comments
Balances <sup>3</sup>	(300 to 1000) g (1000 to 2000) g (2000 to 10 000) g (10 000 to 20 000) g (20 000 to 40 000) g	0.002 % 0.002 % 0.002 % 0.002 % 0.002 %	Verification with Class 1, 3 and F weights
Mass, Fixed Points	(1, 2, 3, 5) mg (10, 20, 30, 50) mg (100, 200, 300) mg 500 mg 1 g 2 g (3, 4, 5) g (10, 20) g (30, 40) g 50 g 100 g 200 g 300 g (400, 500) g 1 kg (2, 3, 4) kg 5 kg 10 kg 20 kg 25 kg  (1/32, 1/16, 1/8) oz (1/4, 1/2) oz (1, 2) oz 4 oz 8 oz 0.001 lb 0.002 lb 0.005 lb 0.01 lb 0.02 lb 0.05 lb 0.1 lb 0.2 lb 1 lb 2 lb (3, 4, 5) lb 10 lb (20, 25) lb 50 lb	0.006 mg 0.006 mg 0.007 mg 0.007 mg 0.01 mg 0.01 mg 0.01 mg 0.02 mg 0.10 mg 0.10 mg 0.10 mg 0.15 mg 20 mg 20 mg 20 mg 20 mg 22 mg 270 mg 250 mg 420 mg  0.000 004 oz 0.000 005 oz 0.000 017 oz 0.000 017 oz 0.000 17 oz 0.000 00022 lb 0.000 00015 lb 0.000 0002 lb 0.000 00015 lb 0.000 00022 lb 0.000 00031 lb 0.000 00057 lb 0.000 00075 lb 0.000 021 lb 0.000 013 lb 0.000 035 lb 0.000 044 lb 0.000 6 lb 0.000 93 lb	Comparison to Class 1 standard weights

Parameter/Equipment	Range	CMC <sup>2,4</sup> (±)	Comments
Scales <sup>3</sup>	(0 to 200 000) lb	0.01 %	Verification with Class F weights
Indirect Verification of Rockwell Hardness Testers <sup>3</sup>	(20 to 30) HRC (35 to 55) HRC (60 to 65) HRC  (40 to 59) HRBW (60 to 79) HRBW (80 to 100) HRBW	0.69 HRC 0.94 HRC 1.6 HRC  2.2 HRBW 0.66 HRBW 0.66 HRBW	Master blocks

#### IV. Thermodynamics

Parameter/Equipment	Range	CMC <sup>2</sup> (±)	Comments
Temperature – Measure <sup>3</sup>	(-200 to 0) °C (0 to 350) °C	3.6 °C 1.7 °C	Fluke 744, SLE type T thermocouple
	(350 to 704) °C (704 to 1250) °C	3.3 °C 5.8 °C	Fluke 744, SLE type K thermocouple
Relative Humidity	(10 to 90) % RH (90 to 98) % RH	2.9 % RH 3.6 % RH	Vaisala HMI-41/HMP -46
Temperature – Thermometers, Temperature Probes	(-20 to 150) °C	0.4 °C	Fluke 1560 Fluke 5699 Temperature Baths

<sup>1</sup> This laboratory offers commercial calibration service and field calibration service.

<sup>2</sup> Calibration and Measurement Capability Uncertainty (CMC) is the smallest uncertainty of measurement that a laboratory can achieve within its scope of accreditation when performing more or less routine calibrations of nearly ideal measurement standards or nearly ideal measuring equipment. CMCs represent expanded uncertainties expressed at approximately the 95 % level of confidence, usually using a coverage factor of  $k = 2$ . The actual measurement uncertainty of a specific calibration performed by the laboratory may be greater than the CMC due to the behavior of the customer's device and to influences from the circumstances of the specific calibration.

- <sup>3</sup> Field calibration service is available for this calibration and this laboratory meets A2LA R104 – *General Requirements: Accreditation of Field Testing and Field Calibration Laboratories* for these calibrations. Please note the actual measurement uncertainties achievable on a customer's site can normally be expected to be larger than the CMC found on the A2LA Scope. Allowance must be made for aspects such as the environment at the place of calibration and for other possible adverse effects such as those caused by transportation of the calibration equipment. The usual allowance for the actual uncertainty introduced by the item being calibrated, (e.g. resolution) must also be considered and this, on its own, could result in the actual measurement uncertainty achievable on a customer's site being larger than the CMC.
- <sup>4</sup> In the statement of CMC,  $R$  is the numerical value of the resolution of the device in pounds-force or in microinches, % IV indicates percentage of indicated value, and  $L$  is the numerical value of the nominal length of the device measured in inches.  $D$  is the numerical value of the nominal diameter of the device measured in inches.
- <sup>5</sup> “Labmaster Universal” and “Supermicrometer” are registered trademarks with a last listed owner of Pratt & Whitney Measurement Systems, Inc., Connecticut U.S.A.
- <sup>6</sup> The stated measured values are determined using the indicated instrument (see Comments). This capability is suitable for the calibration of the devices intended to measure or generate the measured value in the ranges indicated. CMCs are expressed as either a specific value that covers the full range or as a fraction/percentage of the reading plus a fixed floor specification.





## *Accredited Laboratory*

A2LA has accredited

# GRAND RAPIDS METROLOGY

*Grand Rapids, MI*

for technical competence in the field of

## Calibration

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2005 *General requirements for the competence of testing and calibration laboratories*. This laboratory also meets the requirements of ANSI/NCSLI Z540-1-1994 and any additional program requirements in the field of calibration. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated 8 January 2009).



Presented this 15<sup>th</sup> day of December 2015.

A handwritten signature in black ink, appearing to read "L. J. ...", positioned above a horizontal line.

President and CEO  
For the Accreditation Council  
Certificate Number 1489.01  
Valid to January 31, 2018  
Revised December 21, 2017

*For the calibrations to which this accreditation applies, please refer to the laboratory's Calibration Scope of Accreditation.*